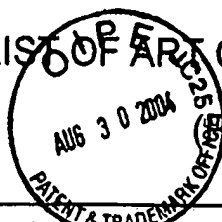


## LIST OF ART CITED BY APPLICANT



TO-1449)

ATTY. DOCKET NO.  
SEKI-0005APPLN. SERIAL NO.  
09/889,160APPLICANT(S)  
Yutaka YASUKURAFILING DATE  
July 11, 2001GROUP  
2182 2132

## U.S. PATENT DOCUMENTS

EXAMINER'S INITIALS	*PATENT NO.	*ISSUE DATE	*INVENTOR NAME	CLASS	SUBCLASS	FILING DATE

RECEIVED

SEP 01 2004

Technology Center 2100

## U.S. PATENT APPLICATION PUBLICATIONS

*PATENT APPLN. PUB. NO.	*PUB. DATE	*APPLICANT	CLASS	SUBCLASS

## U.S. PATENT APPLICATIONS

*APPLN. NO.	*FILING DATE	*INVENTOR	CLASS	SUBCLASS

## FOREIGN PATENT DOCUMENTS

EXAMINER'S INITIALS	PATENT NO.	DATE	COUNTRY	CLASS	SUBCLASS	Translation	
						Yes	No
VP	JP 3151738	6/27/1991	JAPAN (Full Japanese Text)			Abst. only	
VP	JP 63225840	9/20/1988	JAPAN (Full Japanese Text)			Abst. only	
VP	JP 61107375	5/26/1986	JAPAN (Full Japanese Text)				X
VP	JP 60247683	12/7/1985	JAPAN (Full Japanese Text)				X

## OTHER ART (Including Author, Title, Date, Pertinent Pages, Publisher, Place of Publication, Etc.)


EXAMINER

Vulbert Henningsen

DATE CONSIDERED

12/27/04

EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; draw line through citation if not in conformance and not considered. Include copy of this form with next communication to Applicant.

BEST AVAILABLE COPY

LIST OF PRIOR ART CITED BY  
APPLICANT

(PTO-1449)

ATTY. DOCKET NO.  
SEKI-0005APPLN. SERIAL NO.  
09/889,160  
Intl. Appln. No.  
PCT/JP99/01350APPLICANT(S)  
Yutaka YASUKURA

CUSTOMER NO. 34610

FILING DATE  
International Filing  
Date: March 18, 1999  
U.S. Natl. Phase  
Filing Date: July 11,  
2001GROUP  
2182

2132

## U.S. PATENT DOCUMENTS

EXAMINER'S INITIALS	*PATENT NO.	*ISSUE DATE	*INVENTOR NAME	CLASS	SUBCLASS	FILING DATE

RECEIVED

APR 26 2004

Technology Center 200

## U.S. PATENT APPLICATION PUBLICATIONS

	*PATENT APPLN. PUB. NO.	*PUB. DATE	*APPLICANT	CLASS	SUBCLASS	

## U.S. PATENT APPLICATIONS

	*APPLN. NO.	*FILING DATE	*INVENTOR	CLASS	SUBCLASS	

## FOREIGN PATENT DOCUMENTS

EXAMINER'S INITIALS	PATENT NO.	DATE	COUNTRY	CLASS	SUBCLASS	Translation	
						Yes	No
VP	WO 00/64096	10-26-00	WIPO			X	
VP	DE 2641337A	03-16-78	Germany				X

## OTHER ART (Including Author, Title, Date, Pertinent Pages, Publisher, Place of Publication, Etc.)

VP	A. Menezes et al. "Handbook for Applied Cryptography" 1996 CRC PRESS XP002246921, ISBN: 0-8493-8523-7, pp. 543-550

EXAMINER

Verhat Pungarvor

DATE CONSIDERED

12/27/04

EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; draw line through citation if not in conformance and not considered. Include copy of this form with next communication to Applicant.

LIST OF PRIOR ART CITED BY  
APPLICANT

(PTO-1449)

ATTY. DOCKET NO.  
SEKI-0005APPLN. SERIAL NO.  
09/889,160  
Intl. Appln. No.  
PCT/JP99/01350APPLICANT(S)  
Yutaka YASUKURAFILING DATE  
International Filing  
Date: March 18, 1999  
U.S. Natl. Phase Filing  
Date: July 11, 2001GROUP  
2182

2172

## U.S. PATENT DOCUMENTS

EXAMINER'S INITIALS	*PATENT NO.	*ISSUE DATE	*INVENTOR NAME	CLASS	SUBCLASS	FILING DATE
VP	4,933,969	06-12-90	Marshall et al.	380	125	03-01-88

## U.S. PATENT APPLICATION PUBLICATIONS

*PATENT APPLN. PUB. NO.	*PUB. DATE	*APPLICANT	CLASS	SUBCLASS

## U.S. PATENT APPLICATIONS

*APPLN. NO.	*FILING DATE	*INVENTOR	CLASS	SUBCLASS

## FOREIGN PATENT DOCUMENTS

EXAMINER'S INITIALS	PATENT NO.	DATE	COUNTRY	CLASS	SUBCLASS	Translation	
						Yes	No
VP	JP 3-151738A	06-27-91	Japan			X	
VP	JP 8-185376A	07-16-96	Japan			X	
VP	JP 10-91705A	04-10-98	Japan			X	
VP	JP 63-255840A	09-20-88	Japan			X	
VP	JP 62-72243A	04-02-87	Japan			X	
VP	JP 2-259689A	10-22-90	Japan			X	
VP	JP 60-247683A	12-07-85	Japan			X	
VP	JP 61-107375A	05-26-86	Japan			X	

RECEIVED

JUN 06 2002

Technology Center 2100

## OTHER ART (Including Author, Title, Date, Pertinent Pages, Publisher, Place of Publication, Etc.)


EXAMINER

Vebert Rungmoo

DATE CONSIDERED

12/27/04

<b>LIST OF PRIOR ART CITED BY APPLICANT</b>  <b>(PTO-1449)</b>				ATTY. DOCKET NO. <b>SEKI-0005</b>		APPLN. SERIAL NO. <b>09/889,160</b>	
				APPLICANT(S) <b>Yutaka YASUKURA</b>			
				FILING DATE International Filing Date: March 18, 1999 U.S. Natl. Phase Filing Date: July 11, 2001		GROUP <del>art unit</del>  <b>2132</b>	
<b>U.S. PATENT DOCUMENTS</b>							
EXAMINER'S INITIALS	*PATENT NO.	*ISSUE DATE	*INVENTOR NAME	CLASS	SUBCLASS	FILING DATE	
<b>U.S. PATENT APPLICATION PUBLICATIONS</b>							
	*PATENT APPLN. PUB. NO.	*PUB. DATE	*APPLICANT	CLASS	SUBCLASS		
<b>U.S. PATENT APPLICATIONS</b>							
	*APPLN. NO.	*FILING DATE	*INVENTOR	CLASS	SUBCLASS		
<b>FOREIGN PATENT DOCUMENTS</b>							
EXAMINER'S INITIALS	PATENT NO.	DATE	COUNTRY	CLASS	SUBCLASS	Translation	
						Yes	No
<i>VP</i>	JP 62-72243A	04-02-87	Japan				
<i>VP</i>	JP 2-259689A	10-22-90	Japan				
<b>OTHER ART (Including Author, Title, Date, Pertinent Pages, Publisher, Place of Publication, Etc.)</b>							
EXAMINER	<i>Verlief Pennington</i>			DATE CONSIDERED <i>12/27/09</i>			

EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; draw line through citation if not in conformance and not considered. Include copy of this form with next communication to Applicant.

**This Page is Inserted by IFW Indexing and Scanning  
Operations and is not part of the Official Record**

**BEST AVAILABLE IMAGES**

Defective images within this document are accurate representations of the original documents submitted by the applicant.

Defects in the images include but are not limited to the items checked:

- ☐ BLACK BORDERS
- ☐ IMAGE CUT OFF AT TOP, BOTTOM OR SIDES
- ☐ FADED TEXT OR DRAWING
- ☐ BLURRED OR ILLEGIBLE TEXT OR DRAWING
- ☐ SKEWED/SLANTED IMAGES
- ☐ COLOR OR BLACK AND WHITE PHOTOGRAPHS
- ☐ GRAY SCALE DOCUMENTS
- ☐ LINES OR MARKS ON ORIGINAL DOCUMENT
- ☐ REFERENCE(S) OR EXHIBIT(S) SUBMITTED ARE POOR QUALITY
- ☐ OTHER: \_\_\_\_\_

**IMAGES ARE BEST AVAILABLE COPY.**

As rescanning these documents will not correct the image problems checked, please do not report these problems to the IFW Image Problem Mailbox.